



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

N - CHANNEL ENHANCEMENT MODE POWER MOSFET

SGT MOS、低内阻、低结电容开关损耗小

TF010N04NG**• General Description**

The TF010N04NG uses advanced trench technology and design to provide excellent RDS(ON) withlowgate charge. It can be used in a wide variety of applications.

• Features

Advance device constructure

Low $R_{DS(ON)}$ to minimize conduction loss

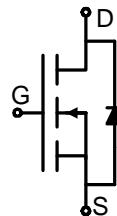
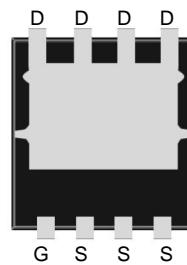
Low Gate Charge for fast switching

Low Thermal resistance

• Application

Synchronous Rectification for AC-DC/DC-DC converter

Power Tools

• Product Summary $V_{DS} = 40V \quad I_D = 190A$ $R_{DS(ON)(10V\ typ)} = 0.9m\Omega$ $R_{DS(ON)(4.5V\ typ)} = 1.4m\Omega$ **PDFNWB5x6-8L****• Package Marking and Ordering Information:**

Part NO.	TF010N04NG
Marking1	010N04NG
Marking2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

• Absolute Maximum Ratings ($T_C = 25^\circ C$)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	190	A
	$I_D @ T_C = 75^\circ C$	135	A
	$I_D @ T_C = 100^\circ C$	115	A
Pulsed Drain Current ^①	I_{DM}	570	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	178	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	3.0	W
Operating Junction Temperature	T_J	-55 to 150	$^\circ C$
Storage Temperature	T_{STG}	-55 to 150	$^\circ C$
Single Pulse Avalanche Energy	E_{AS}	678	mJ



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Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R _{thJC}	-	-	0.7	° C/W
Thermal resistance, junction - ambient	R _{thJA}	-	-	40	° C/W
Soldering temperature, wavesoldering for 8 s	T _{sold}	-	-	265	° C

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D = 250uA	40	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250uA	1.1	1.5	2.1	V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =38 V _{GS} = 0V	-	-	1.0	uA
Gate- Source Leakage Current	I _{GSS}	V _{GS} =±20V , V _{DS} =0V	-	-	±100	nA
Static Drain-source On Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =30A	-	0.9	1.3	mΩ
		V _{GS} =4.5V, I _D =30A	-	1.4	2.3	mΩ
Forward Transconductance	g _{FS}	V _{DS} =25V, I _D =30A	-	45	-	S
Source-drain voltage	V _{SD}	I _S =30A	-	-	1.2	V

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C _{iss}	f = 1MHz V _{DS} =20V V _{GS} = 0V	-	8429	-	pF
Output capacitance	C _{oss}		-	1506	-	
Reverse transfer capacitance	C _{rss}		-	1428	-	

•Gate Charge characteristics(T_a = 25°C)

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Gate Resistance	R _g	f = 1MHz		1.0		Ω
Total gate charge	Q _g	V _{DD} = 20V I _D = 30A V _{GS} = 10V	-	223	-	nC
Gate - Source charge	Q _{gs}		-	35	-	
Gate - Drain charge	Q _{gd}		-	51	-	
Turn-ON Delay time	t _{D(on)}	V _{GS} =10V ,V _{DS} =20V R _G = 1.6Ω,I _D = 30A		16.5		ns
Turn-ON Rise time	t _r			9.00		ns
Turn-Off Delay time	t _{D(off)}			69.0		ns
Turn-Off Fall time	t _f			13.0		ns
Reverse Recovery Time	trr	V _{GS} = 0V, I _S = I _f dI _S /dt = 100A/μs		38.0		ns
Reverse Recovery Charge	Qrr			123		nC

Note: ① Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% ;



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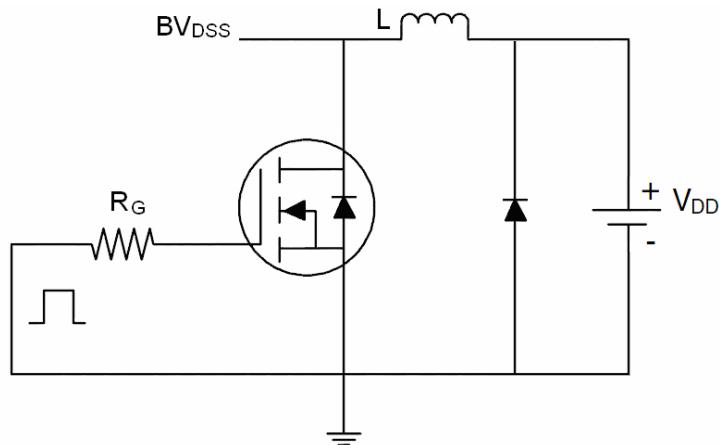
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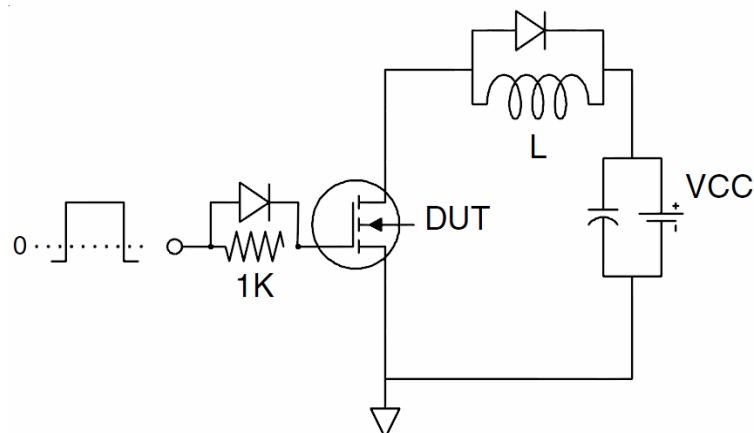
TF010N04NG

Test Circuit

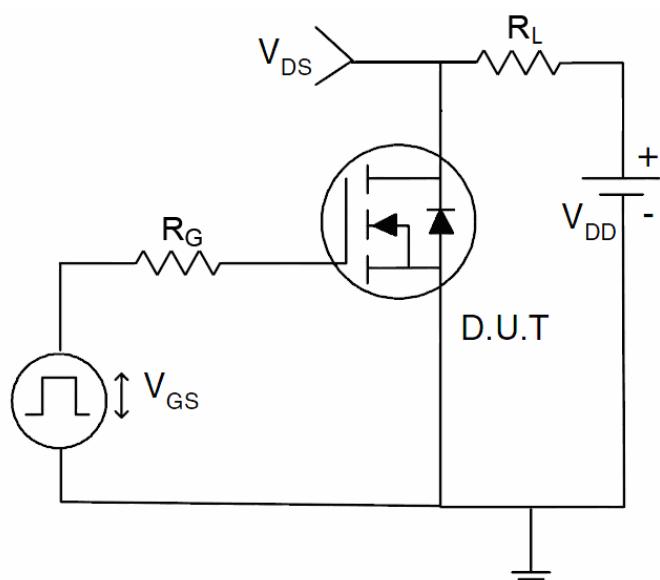
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics

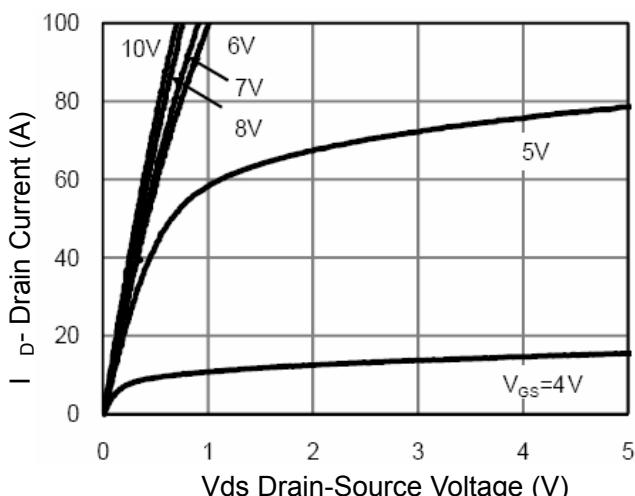


Figure 1 Output Characteristics

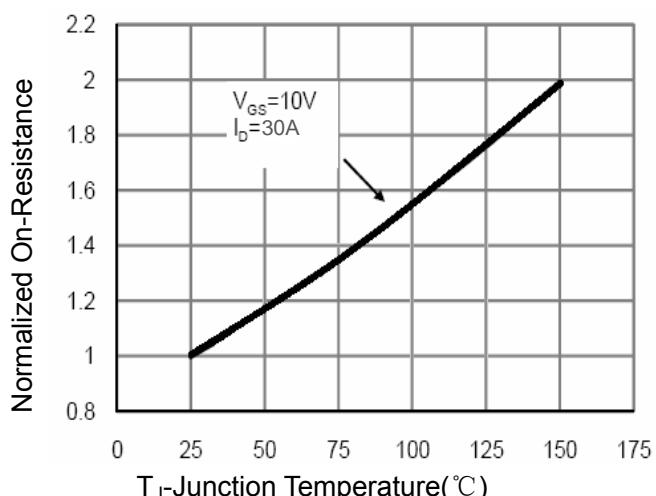


Figure 4 Rdson-JunctionTemperature

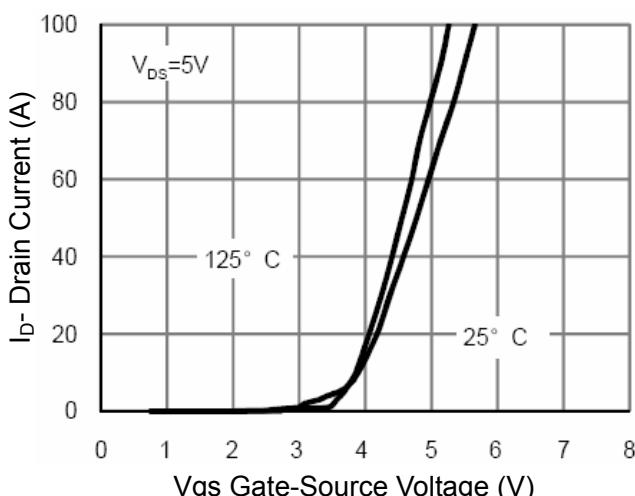


Figure 2 Transfer Characteristics

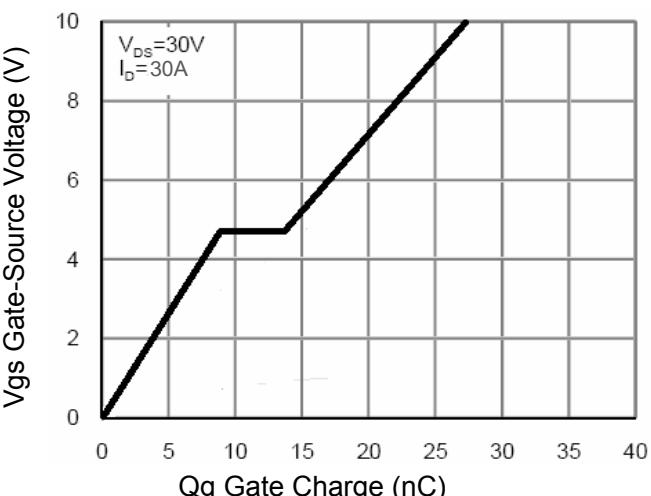


Figure 5 Gate Charge

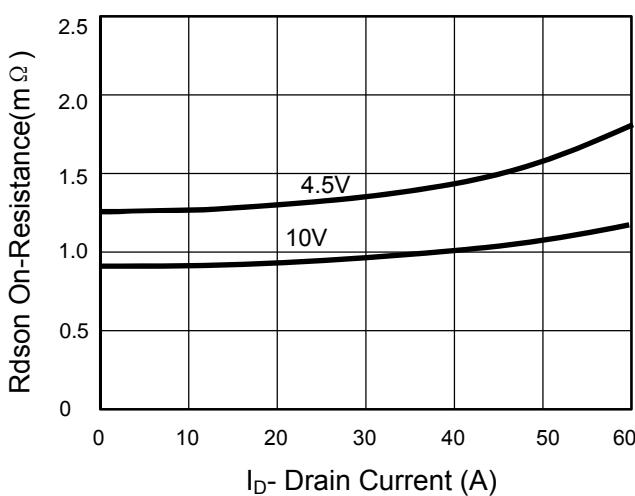


Figure 3 Rdson- Drain Current

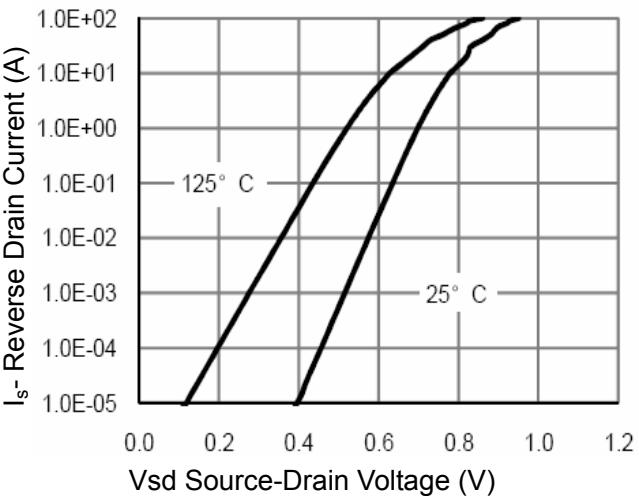


Figure 6 Source- Drain Diode Forward

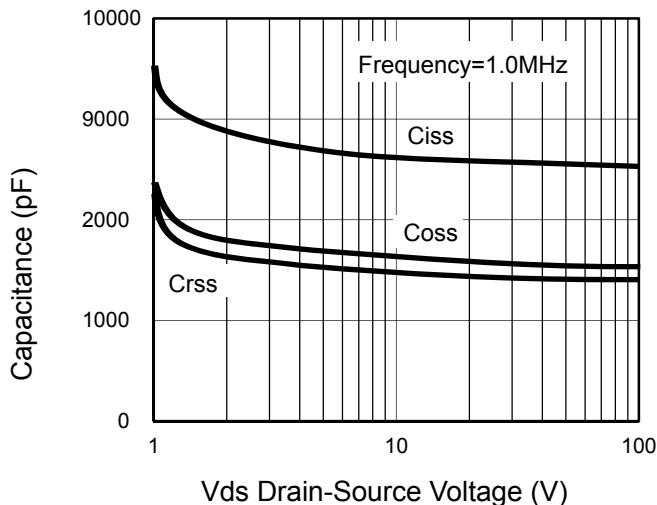


Figure 7 Capacitance vs Vds

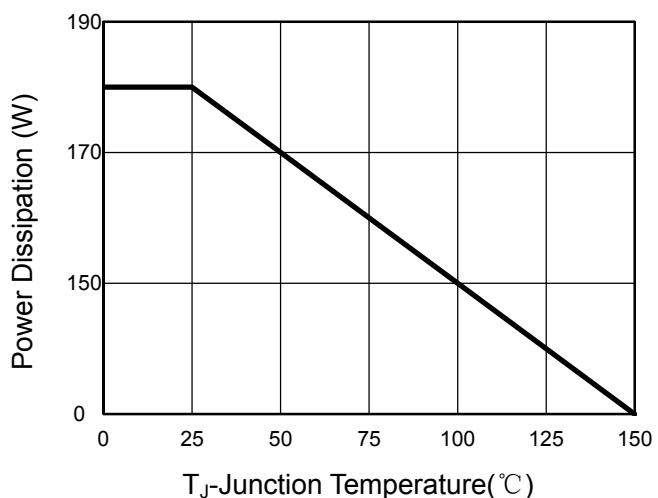


Figure 9 Power De-rating

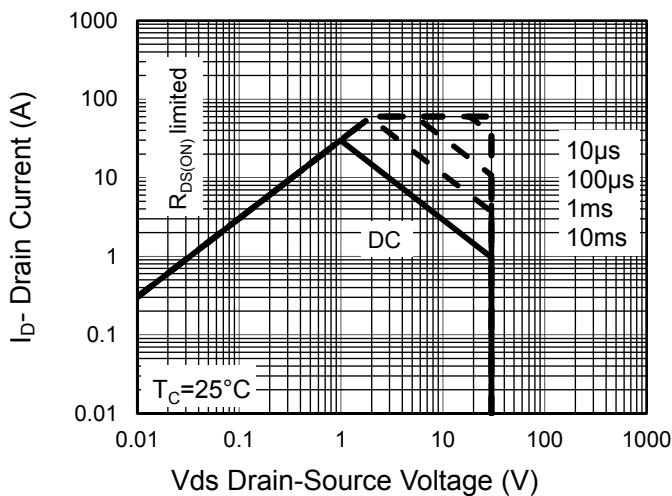


Figure 8 Safe Operation Area

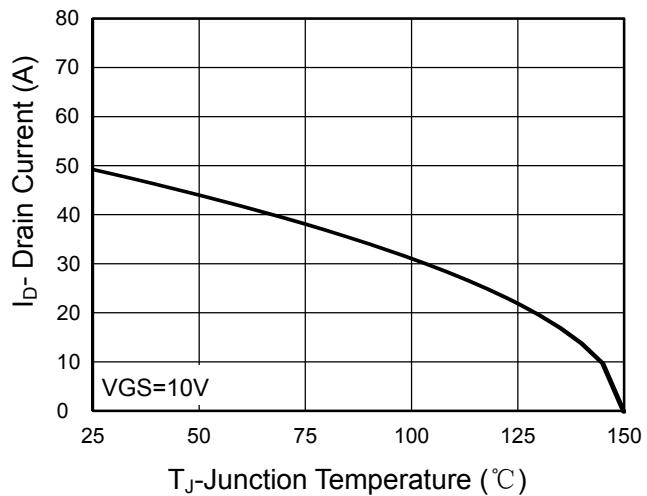


Figure 10 Current De-rating

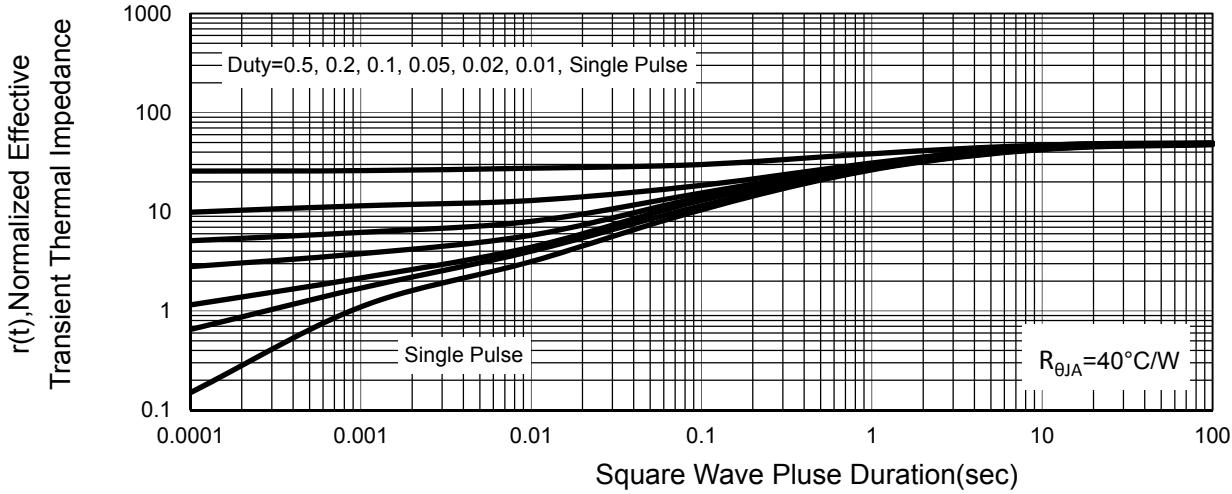
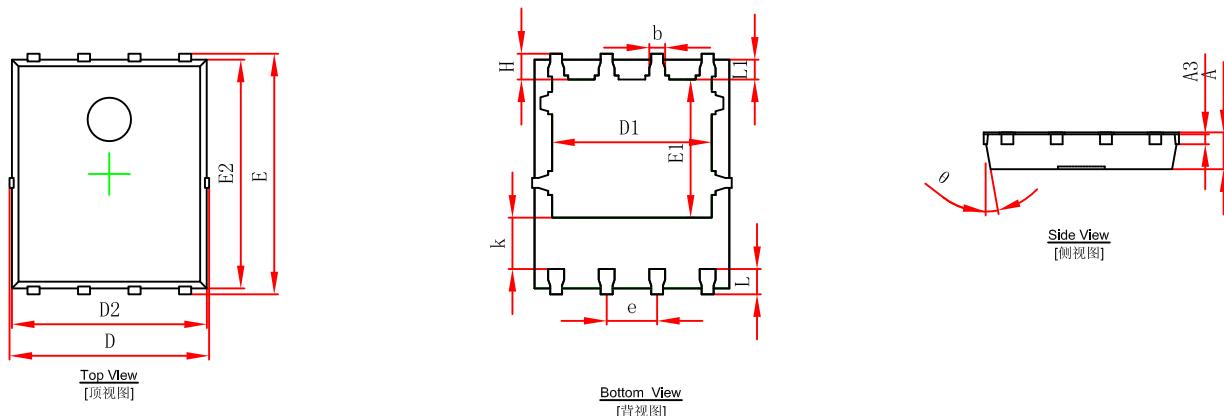


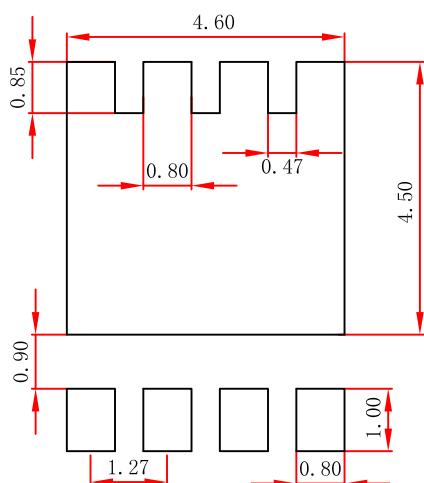
Figure 11 Normalized Maximum Transient Thermal Impedance



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Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

PDFNWB5x6-8L Suggested Pad Layout**Note:**

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.